

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Substitute for form 1449/PTO)			ATTY. DOCKET NO. <b>044117-0143</b>	SERIAL NO. <b>10/539,771</b>			
			APPLICANT <b>Eric PINET, et al.</b>				
			FILING DATE <b>January 10, 2006</b>	GROUP <b>1797</b>			
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sub>2</sub> ( <i>if known</i> )	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
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<b>OTHER ART</b> (Including Author, Title, Date, Pertinent Pages, Etc.)							
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